

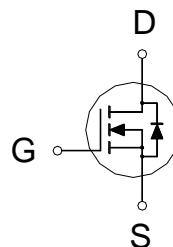
NIKO-SEM**N-Channel Enhancement Mode
Field Effect Transistor****PB6W8BX**

PDFN 2x2S

Halogen-Free & Lead-Free

PRODUCT SUMMARY

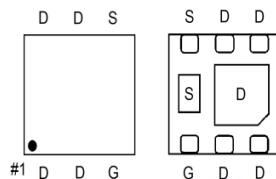
$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
40V	18mΩ	8A

**Features**

- Pb-Free, Halogen Free and RoHS compliant.
- Low $R_{DS(on)}$ to Minimize Conduction Losses.
- Ohmic Region Good $R_{DS(on)}$ Ratio.
- Optimized Gate Charge to Minimize Switching Losses.

Applications

- Protection Circuits Applications.
- Logic/Load Switch Circuits Applications.



G. GATE
D. DRAIN
S. SOURCE

100% UIS Tested
100% Rg Tested

ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNITS
Drain-Source Voltage		V_{DS}	40	V
Gate-Source Voltage		V_{GS}	± 20	V
Pulsed Drain Current ¹		I_{DM}	31	
Continuous Drain Current	$T_A = 25^\circ\text{C}$	I_D	8	A
	$T_A = 70^\circ\text{C}$		6.4	
Avalanche Current		I_{AS}	8.1	
Avalanche Energy	$L = 0.1\text{mH}$	E_{AS}	3.3	mJ
Power Dissipation ³	$T_A = 25^\circ\text{C}$	P_D	2.1	W
	$T_A = 70^\circ\text{C}$		1.4	
Operating Junction & Storage Temperature Range		T_j, T_{stg}	-55 to 150	°C

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THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE		SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient ²	$t \leq 10s$	$R_{\theta JA}$		57	°C / W
Junction-to-Ambient ²	Steady-State	$R_{\theta JA}$		79	

¹Pulse width limited by maximum junction temperature.²The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A = 25^\circ C$.³The Power dissipation is based on $R_{\theta JA} t \leq 10s$ value.**ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ C$, Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	40			
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	1.3	1.7	2.3	V
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0V, V_{GS} = \pm 20V$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 40V, V_{GS} = 0V$			1	
		$V_{DS} = 40V, V_{GS} = 0V, T_J = 55^\circ C$			10	μA
Drain-Source On-State Resistance ¹	$R_{DS(ON)}$	$V_{GS} = 4.5V, I_D = 6.4A$		15	25	
		$V_{GS} = 10V, I_D = 6.4A$		12.4	18	$m\Omega$
Forward Transconductance ¹	g_{fs}	$V_{DS} = 5V, I_D = 6.4A$		32		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 20V, f = 1MHz$		598		
Output Capacitance	C_{oss}			97		pF
Reverse Transfer Capacitance	C_{rss}			76		
Gate Resistance	R_g	$V_{GS} = 0V, V_{DS} = 0V, f = 1MHz$		3.5		Ω
Total Gate Charge ²	Q_g	$V_{DS} = 20V, V_{GS} = 10V, I_D = 6.4A$		17		
				8.7		
Gate-Source Charge ²	Q_{gs}			2.5		
Gate-Drain Charge ²	Q_{gd}			4.2		
Turn-On Delay Time ²	$t_{d(on)}$	$V_{DS} = 20V, I_D \geq 6.4A, V_{GS} = 10V, R_{GEN} = 6\Omega$		7		
Rise Time ²	t_r			28		
Turn-Off Delay Time ²	$t_{d(off)}$			27		
Fall Time ²	t_f			42		nS

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SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ\text{C}$)

Continuous Current	I_S				1.6	A
Forward Voltage	V_{SD}	$I_F = 6.4\text{A}, V_{GS} = 0\text{V}$			1.3	V
Reverse Recovery Time	t_{rr}	$I_F = 6.4\text{A}, dI_F/dt = 100\text{A} / \mu\text{s}$		8.7		nS
Reverse Recovery Charge	Q_{rr}			3.4		nC

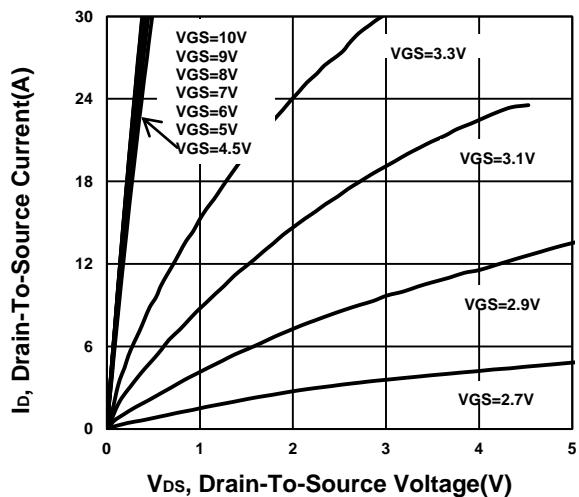
¹Pulse test : Pulse Width $\leq 300\ \mu\text{sec}$, Duty Cycle $\leq 2\%$.²Independent of operating temperature.

NIKO-SEM

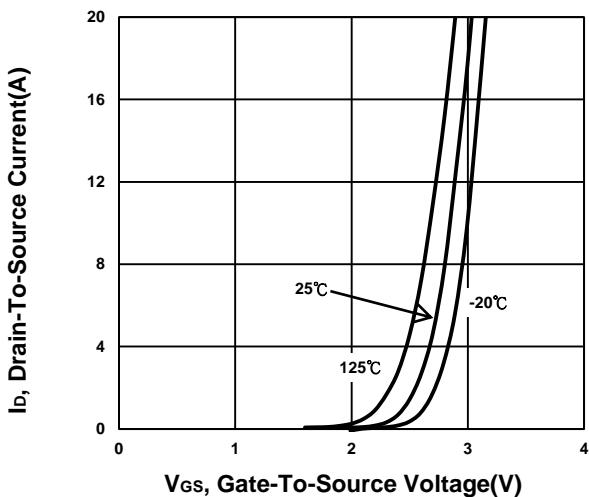
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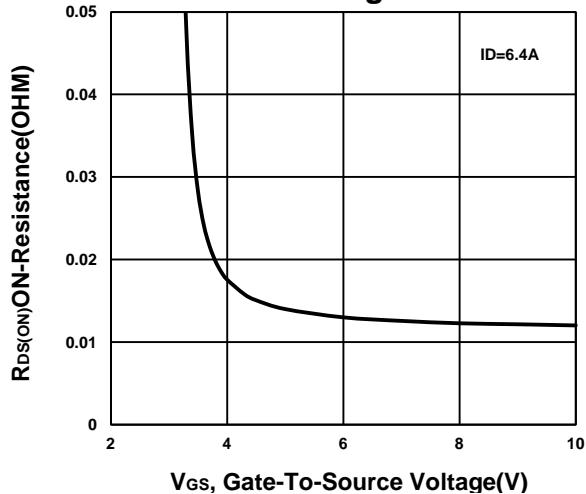
Output Characteristics



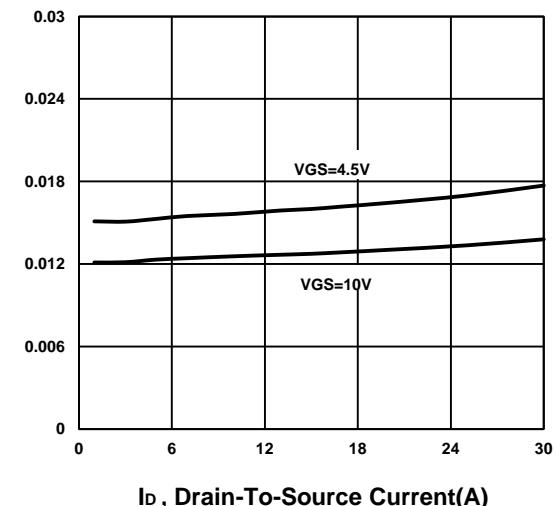
Transfer Characteristics



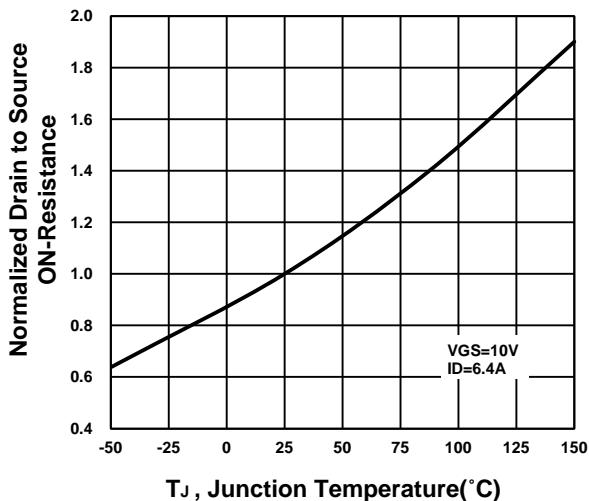
On-Resistance VS Gate-To-Source Voltage



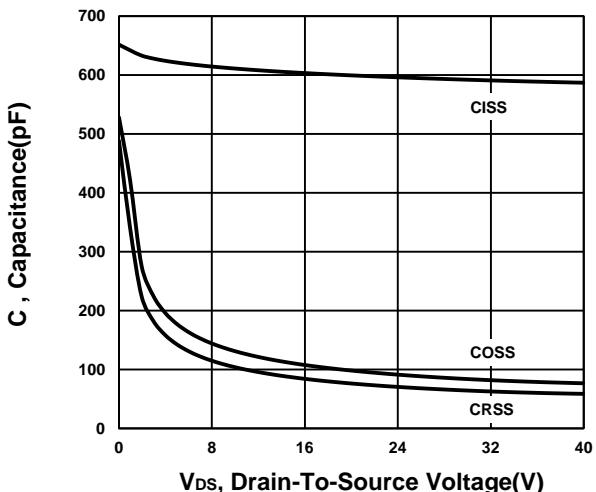
On-Resistance VS Drain Current



On-Resistance VS Temperature



Capacitance Characteristic



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